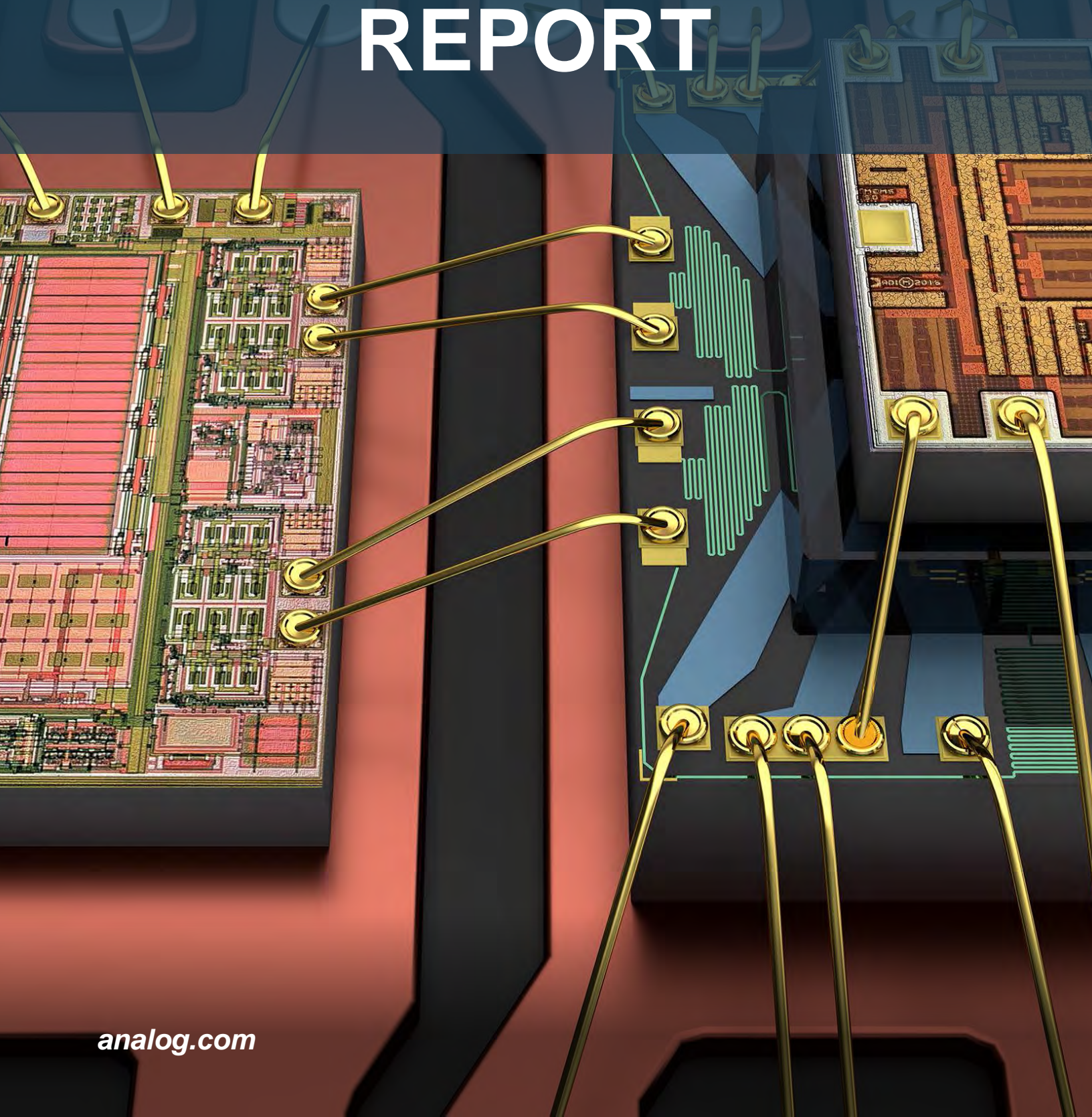


RELIABILITY REPORT





Reliability Data Report Product Family R574

LT3300 \ LT3305

Reliability Data Report

Report Number: R574

Report generated on: Mon Jun 25 07:37:49 PDT 2018

OPERATING LIFE TEST					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS (+125°C) ¹	No. of FAILURES _{2,3}
SSOP/TSSOP	77	1437	1437	77	0
QFP	2940	1246	1611	1923	0
QFN/DFN	77	1231	1231	257	0
Totals	3,094	-	-	2,257	0

HIGHLY ACCELERATED STRESS TEST AT +130 DEG C / 85% RH					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS (+85°C) ⁴	No. of FAILURES
QFP	472	1604	1612	1812	0
Totals	472	-	-	1,812	0

PRESSURE COOKER TEST AT 15 PSIG , +121 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
QFP	875	1313	1644	156	0
Totals	875	-	-	156	0

TEMP CYCLE FROM -65 TO 150 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
QFP	894	1313	1644	1177	0
Totals	894	-	-	1,177	0

THERMAL SHOCK FROM -65 TO 150 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
QFP	332	1313	1644	94	0
Totals	332	-	-	94	0

HIGH TEMPERATURE BAKE AT 150 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
QFP	500	1318	1616	750	0
Totals	500	-	-	750	0

(1) Assumes Activation Energy = 0.7 Electron Volts
 (2) Failure Rate Equivalent to +55 °C, 60% Confidence Level =5.25 FITS
 (3) Mean Time Between Failure in Years = 21744.21
 (4) Assumes 20X Acceleration from 85 °C to +130 °C
 Note 1: 1 FIT = 1 Failure in One Billion Hours.
 Note 2: HAST, Temp Cycle & Thermal Shock are subjected to J-STD-020 MSL Preconditioning

Reliability Data Report

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HIGH TEMPERATURE BAKE AT 175 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
QFP	100	1246	1246	100	0
Totals	100	-	-	100	0